4B: IP Session – Adaptive Test

Organizer: Bob Madge, LSI Logic

Adaptive Test provides exciting possibilities to reduce test cost and increase quality by specifically targeting the parametrics and defects that require the most testing and reducing those that require less. It also provides an opportunity to target low cost testers and address the growing issue of systematic defects. This session will look at Adaptive/Optimal Test innovation from three perspectives. The first talk examines broadly what opportunities and models have been identified for cost and quality improvement. The second is an Industry perspective to show real life examples and issues related to Adaptive Test. The last will be a Commercial perspective to the type of the innovations being made available to the Industry.

Presentations:

Statistical Machine Learning and Its Applications in the Semicon Industry
Randall S. Goodwin, Intel

Adaptive Test – Industrial Examples and Data
Phil Nigh, IBM Microelectronics

Test Cost Reduction Using Optimal Test Methods on Flash Memories and Other Products
Dan Glotter, Optimal Test